

Improved Super Cone

Multipurpose tip for simultaneous measurement of roughness and large step height.

Tip Apex Specifications

Radius:	< 10 nm
Full cone angle:	< 10° for > 3 µm
Tip height:	> 9 µm

Available Cantilevers:

C = 40 N/m, fo = 300 kHz
C = 3.0 N/m, fo = 75 kHz
C = 0.7 N/m, fo = 45 kHz
C = 0.2 N/m, fo = 15 kHz

1 pack includes 5 probe-tips

Probe tips, cantilevers, and cantilever chips consist of single crystal silicon.

All cantilevers are shipped with Al-reflex coating (R).

The ISC probes are also available with alignment grooves on the back side of the holder chip.

Shipments without reflex coating or with special coatings upon request.

All probe tips are SEM quality inspected prior to shipment.

Cantilever Dimensions:

Stiffness	Typical resonant frequency	Length	Width
40 N/m	300 kHz	125 (\pm 15) μ m	35 (\pm 3) μ m
3.0 N/m	75 kHz	225 (\pm 15) μ m	35 (\pm 3) μ m
0.7 N/m	45 kHz	225 (\pm 15) μ m	35 (\pm 3) μ m
0.2 N/m	15 kHz	450 (\pm 15) μ m	35 (\pm 3) μ m

Holder chip dimensions:

Length	3.40 mm
Width	1.55 mm
Thickness	0.315 mm

ISC Lever:	C = 40 N/m,C = 3.0 N/m,C = 0.7 N/m,C = 0.2 N/m
ReflexCoating:	Al-reflex,None